

**Search Notes**

Application/Control No.

10/753,482

Examiner

TUYEN T. NGUYEN

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2832

**SEARCHED**

Class	Subclass	Date	Examiner
336	55-60, 65, 83, 90, 198, 200,	7/24/2005	TTN
336	206-208	7/24/2005	TTN
336	192	7/24/2005	TTN
219	760	7/24/2005	TTN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR